Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/827,285	CHEN ET AL.
Examiner	Art Unit
Devin Hanan	3745

SEARCHED				
Class	Subclass	Date	Examiner	
415	185			
	186R		<u> </u>	
	189			
	178			
	234	9/17/2005	DH	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
consulted Ninh Nguyen on class 415 and 416	9/16/05	DH	